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Determination of FDTR Lateral Resolution for Heterogeneously Integrated Micro Electronics

Rio Grande Symposium on Advanced Materials

Brenden Herkenhoff, Wyatt Hodges, Benjamin Treweek, Amun Jarzembksi, Timothy Walsh, & Gregory Pickrell

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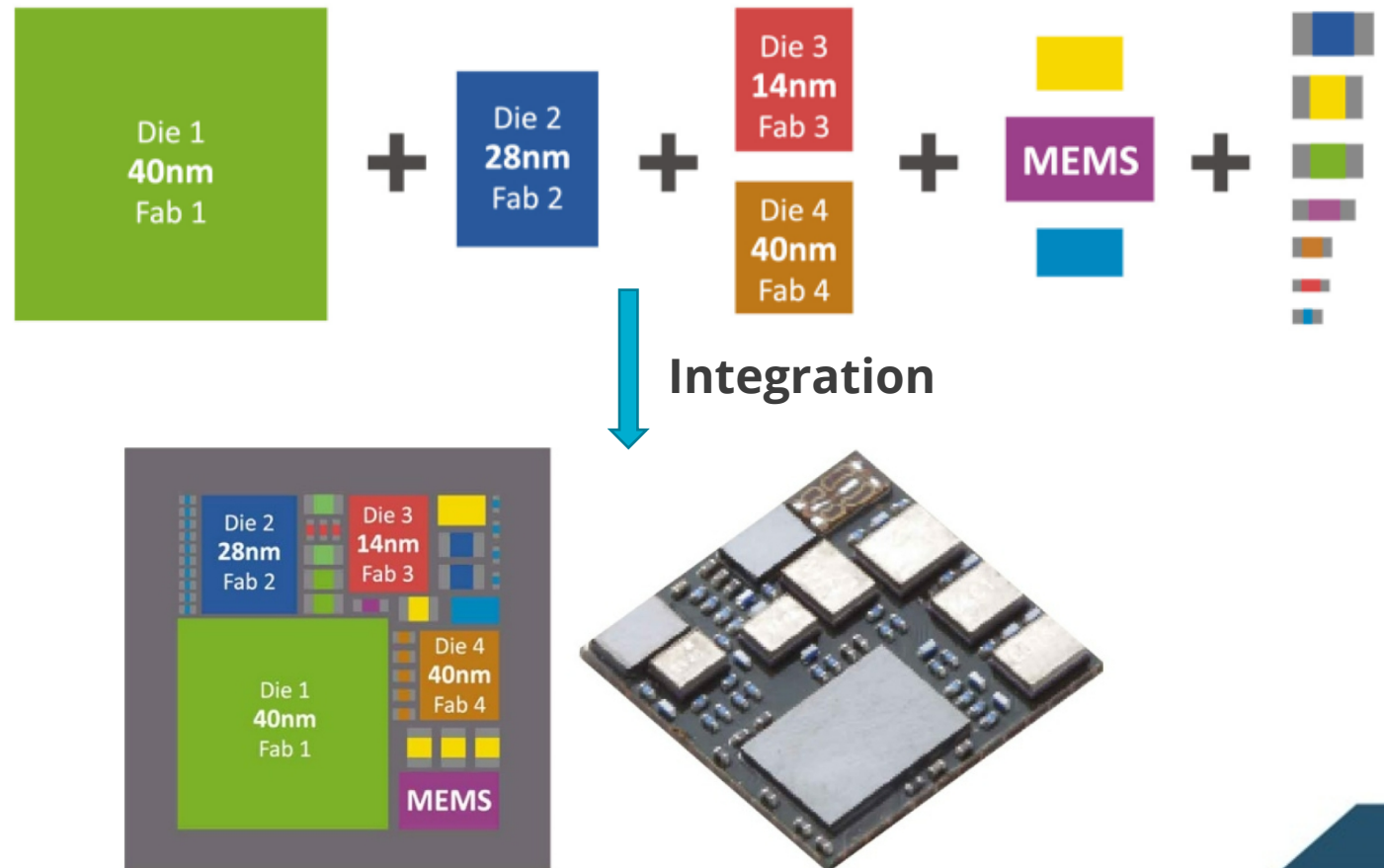
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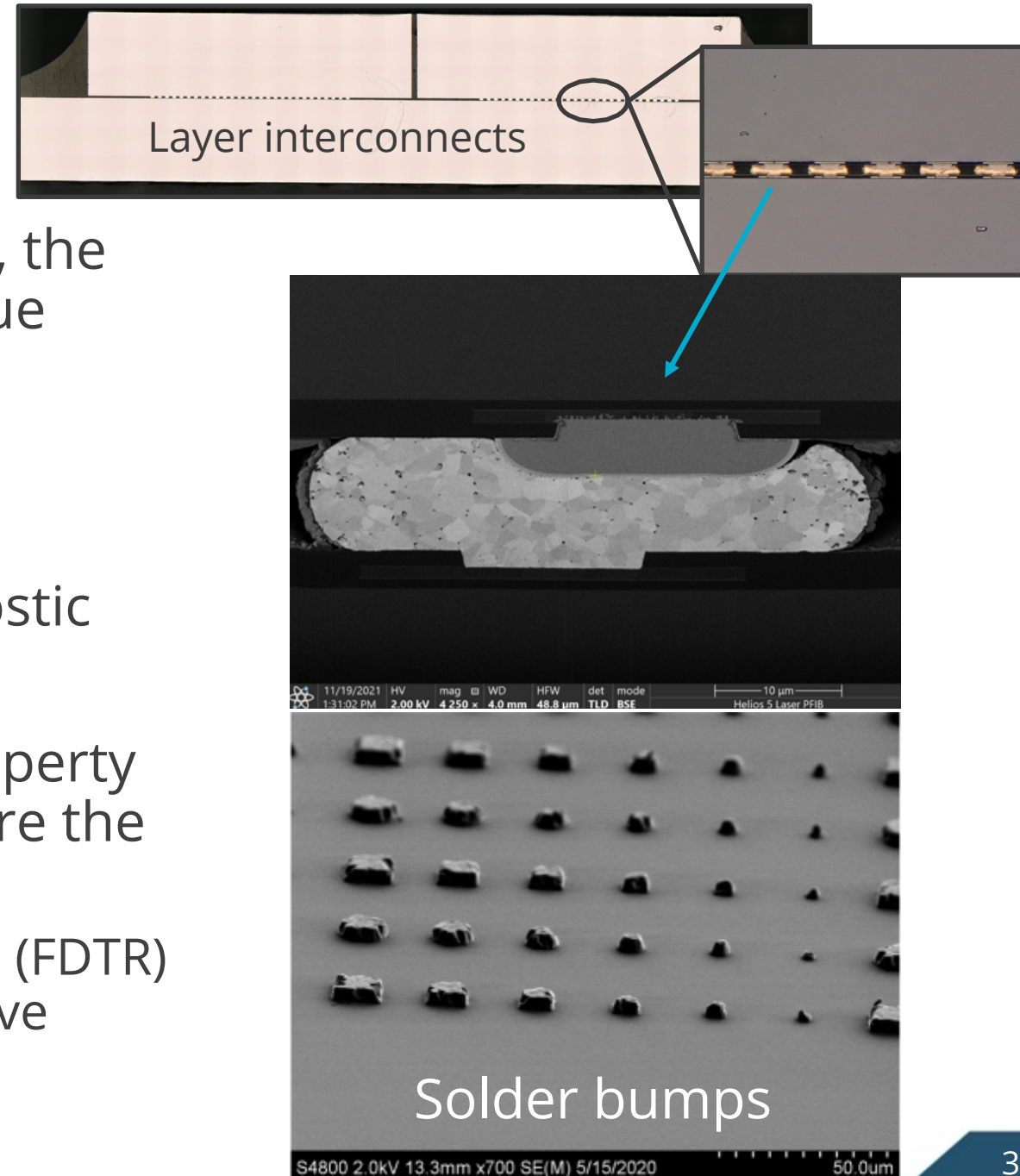
Background

- Thermomechanical simulation for interconnects in heterogeneously integrated (HI) microsystems is challenging, and thus design is challenging
- Several limitations
 - Lack of published knowledge on aging
 - Lack of advanced characterization techniques
 - Limited capabilities



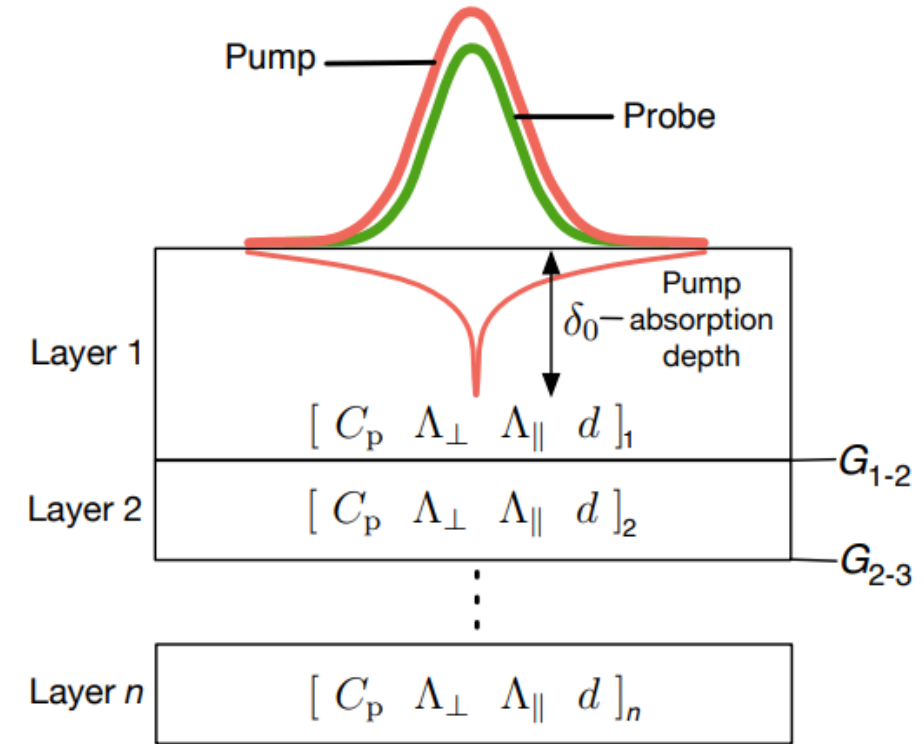
Background

- As manufacturing capability advances, the proliferation of HI systems will continue
 - Increased complexity
 - Subject to thermal and mechanical environmental stress
- Development of high precision diagnostic tools becomes increasingly important
- Previous work has shown thermal property measurements can be used to measure the interfacial properties
 - Frequency Domain Thermoreflectance (FDTR) provides a non contact non-destructive technique



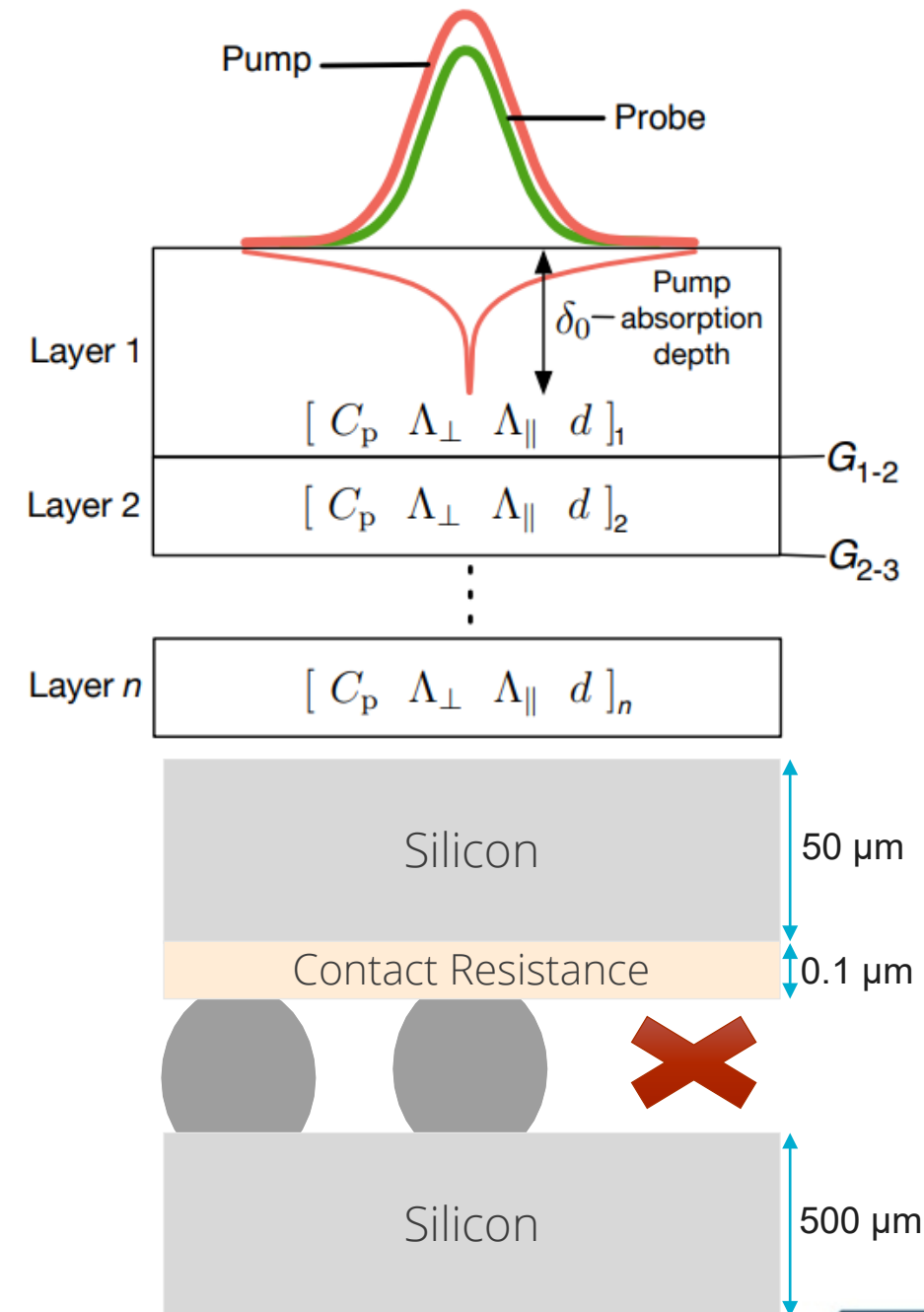
FDTR Overview

- Gaussian beam distribution of pump and probe
- Probe Signal detected by lock-in amplifier
 - Complex frequency response of experimental situation



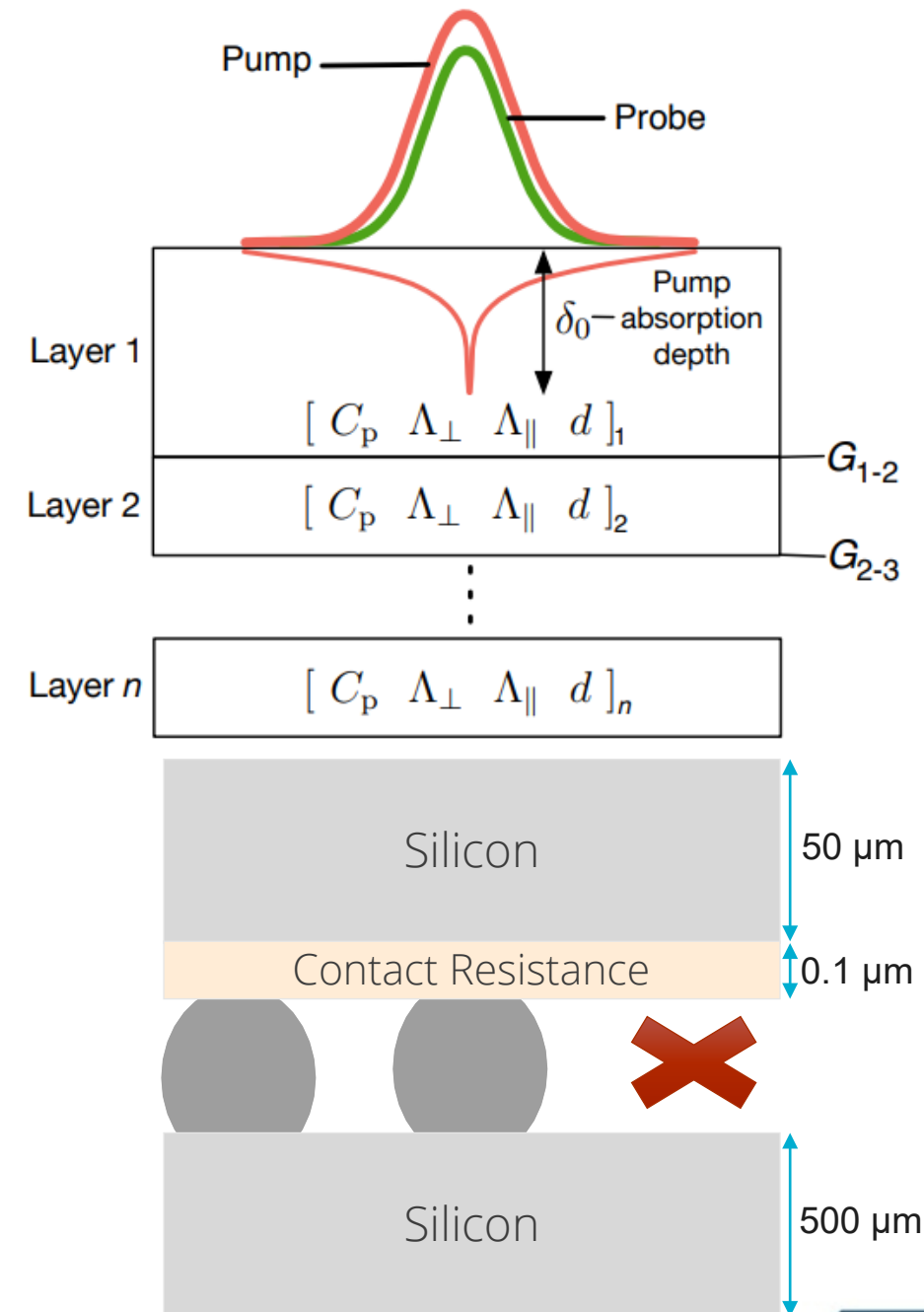
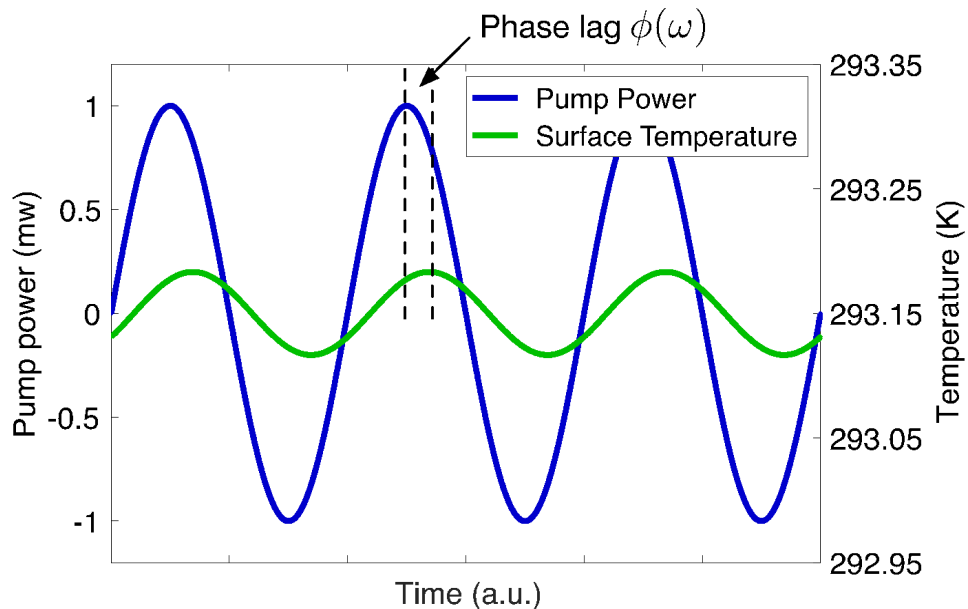
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FDTR Overview

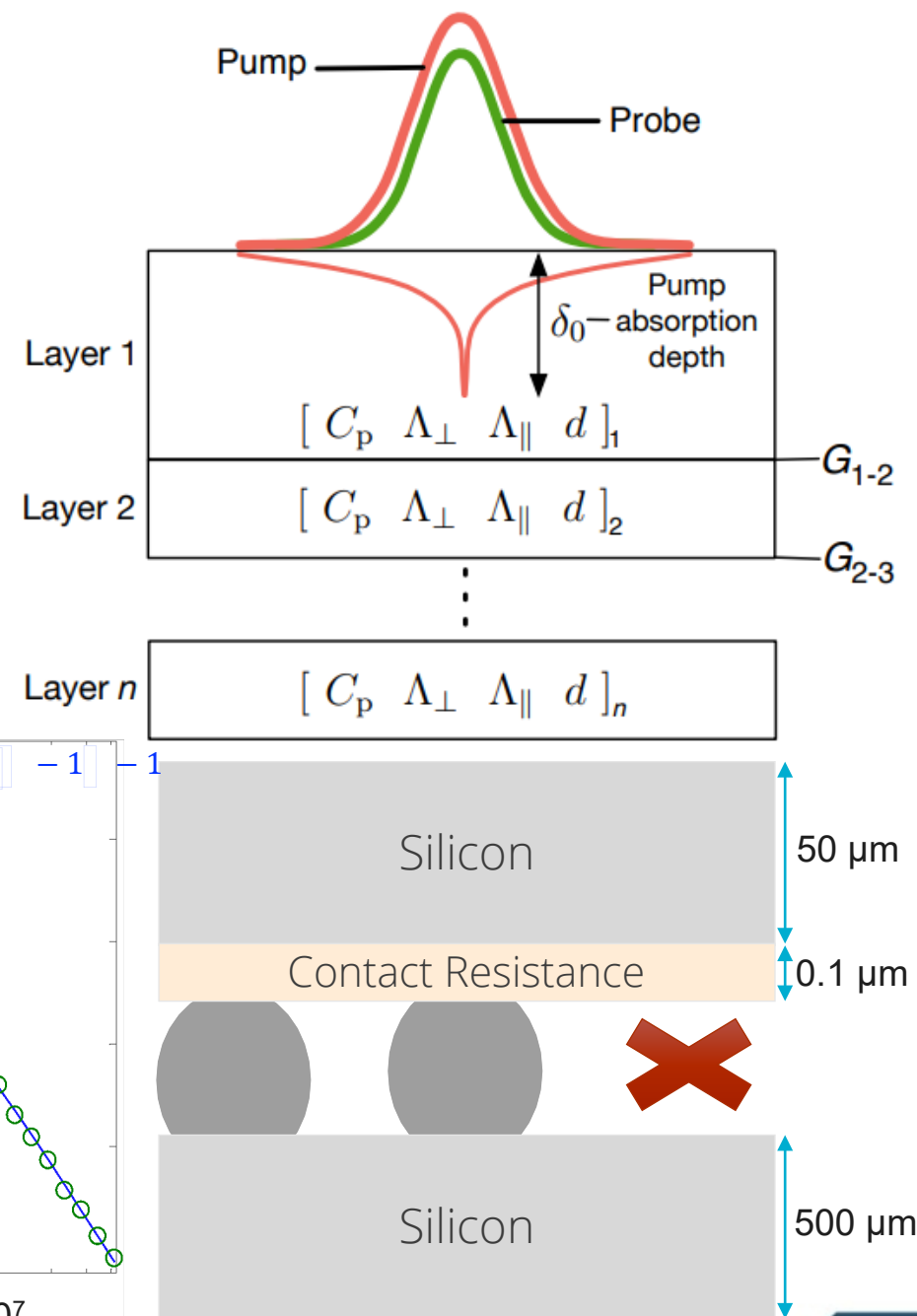
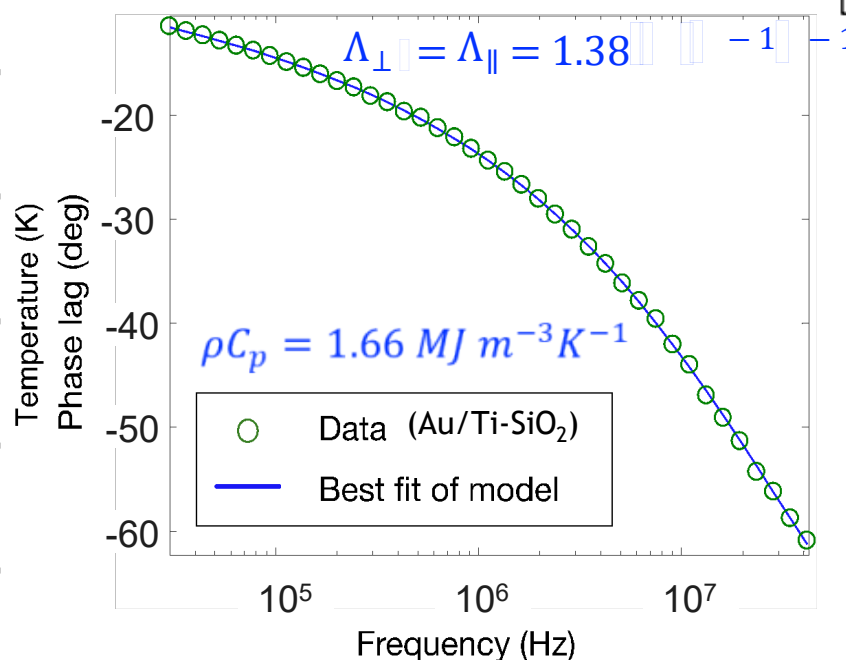
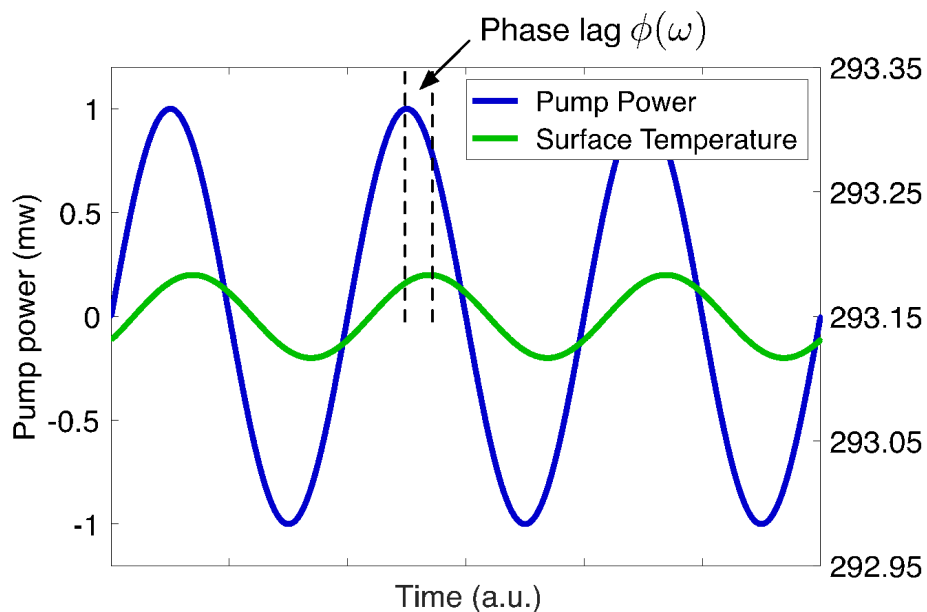
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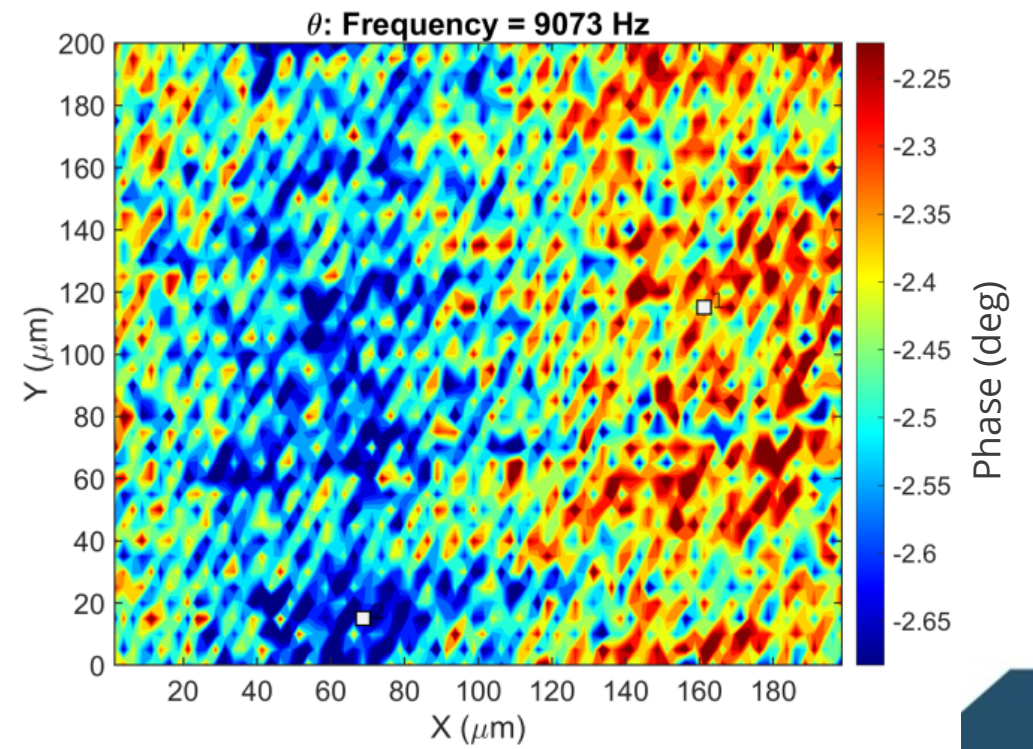
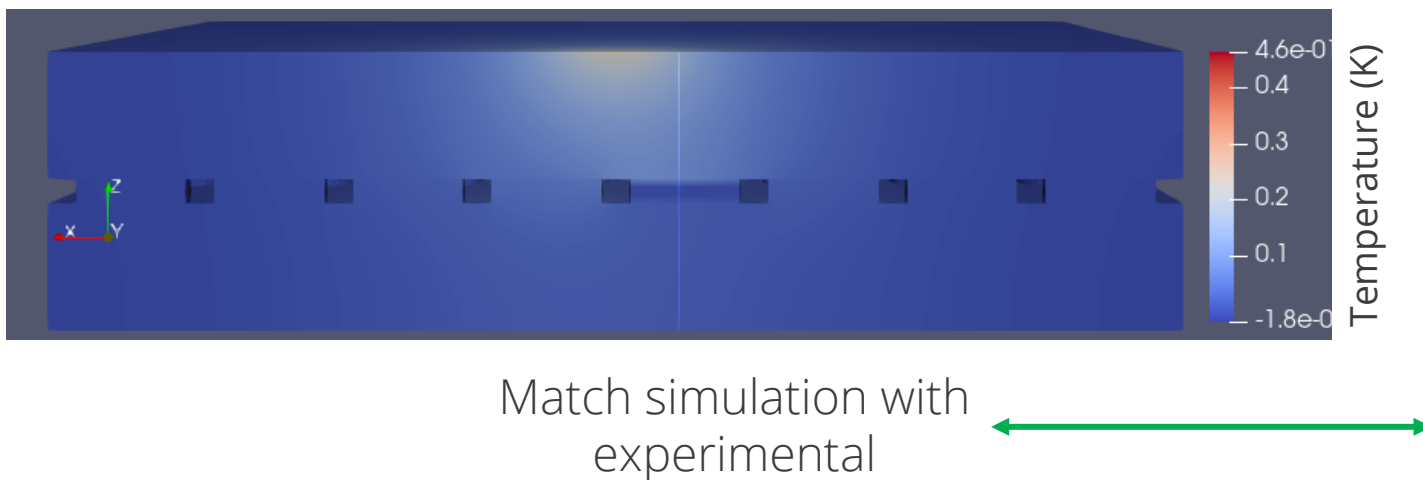
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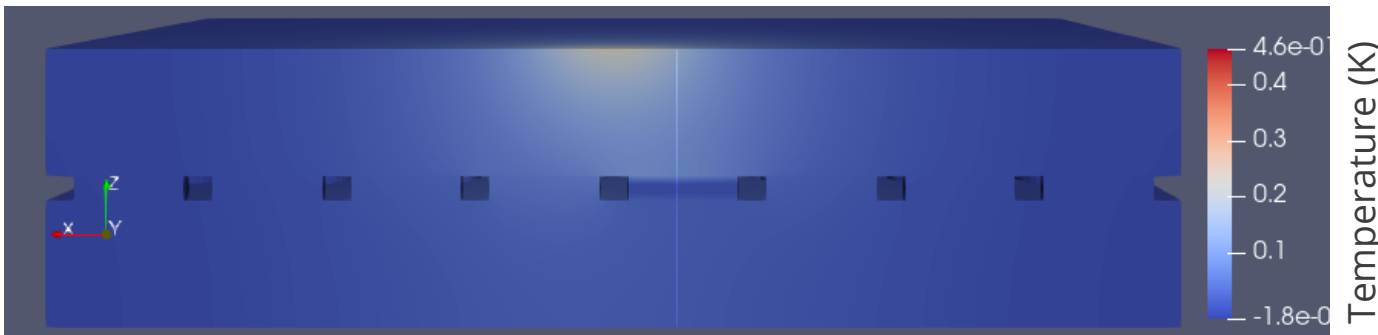
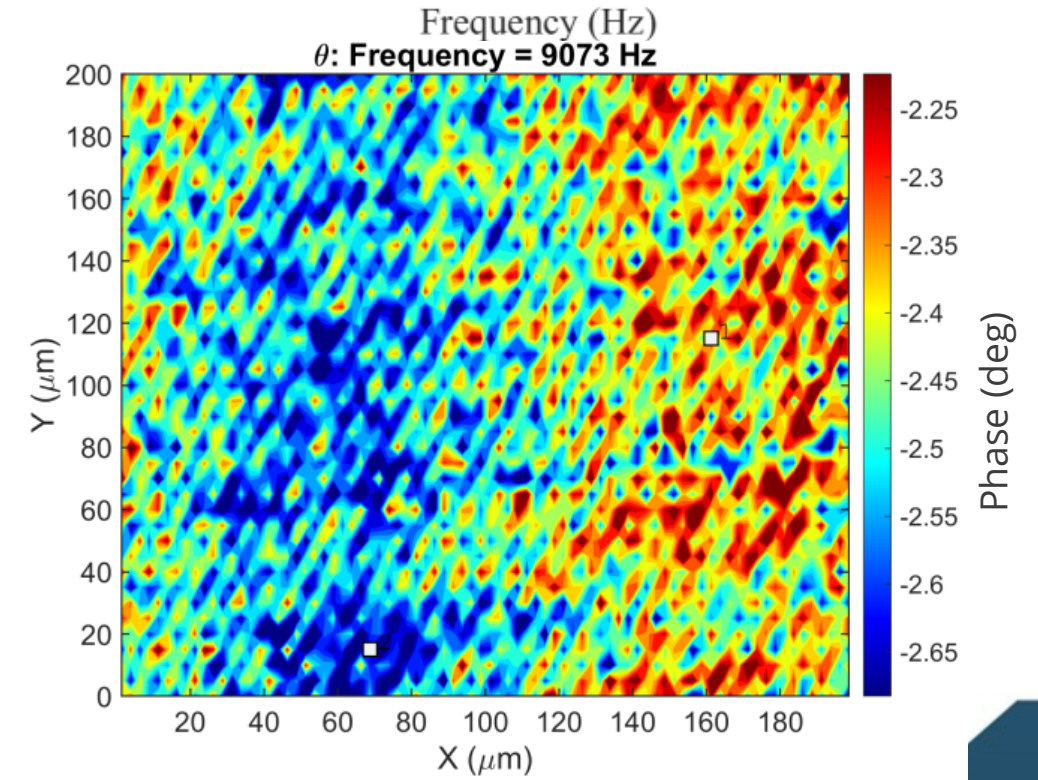
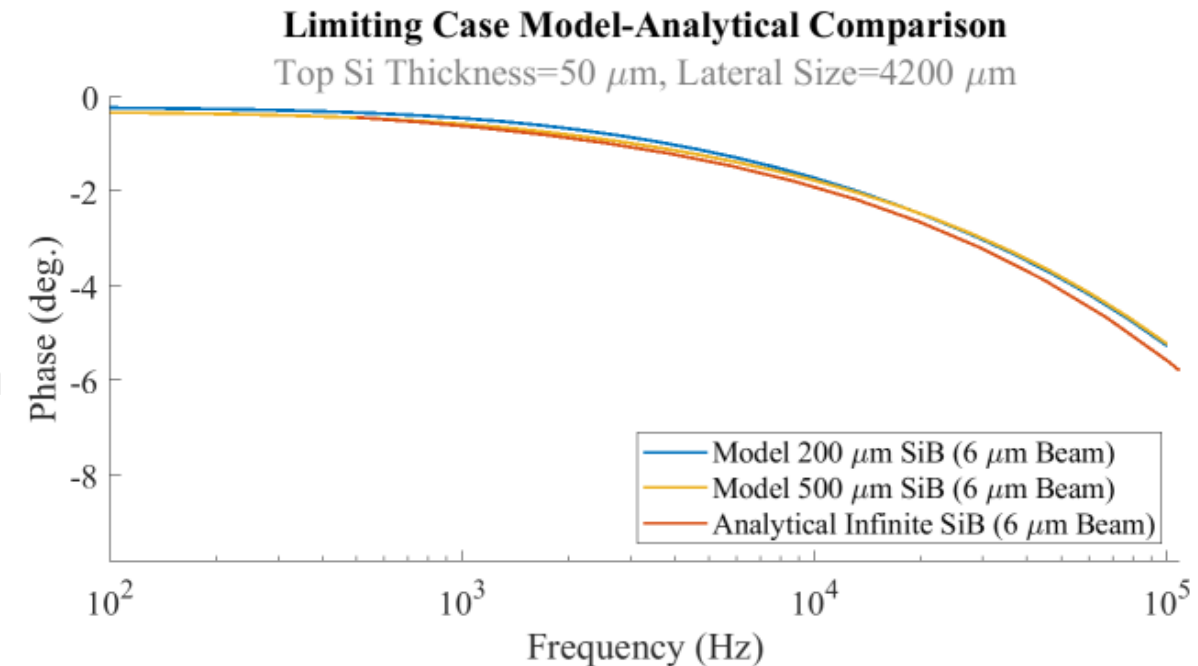
Goal of Current Work

- Model the limits of FDTR
 - Lateral resolution capability and depth variation for varying geometry
- Match simulations to corresponding experiments
- Viability of interconnects



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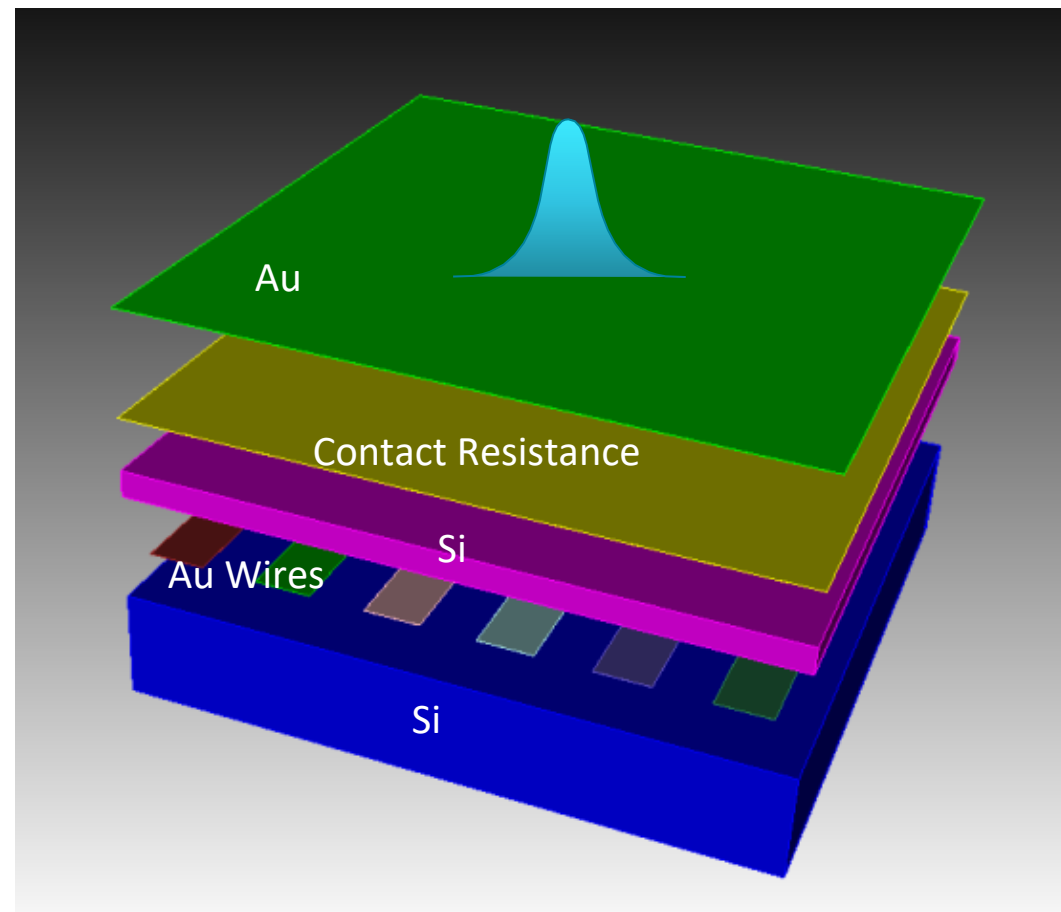
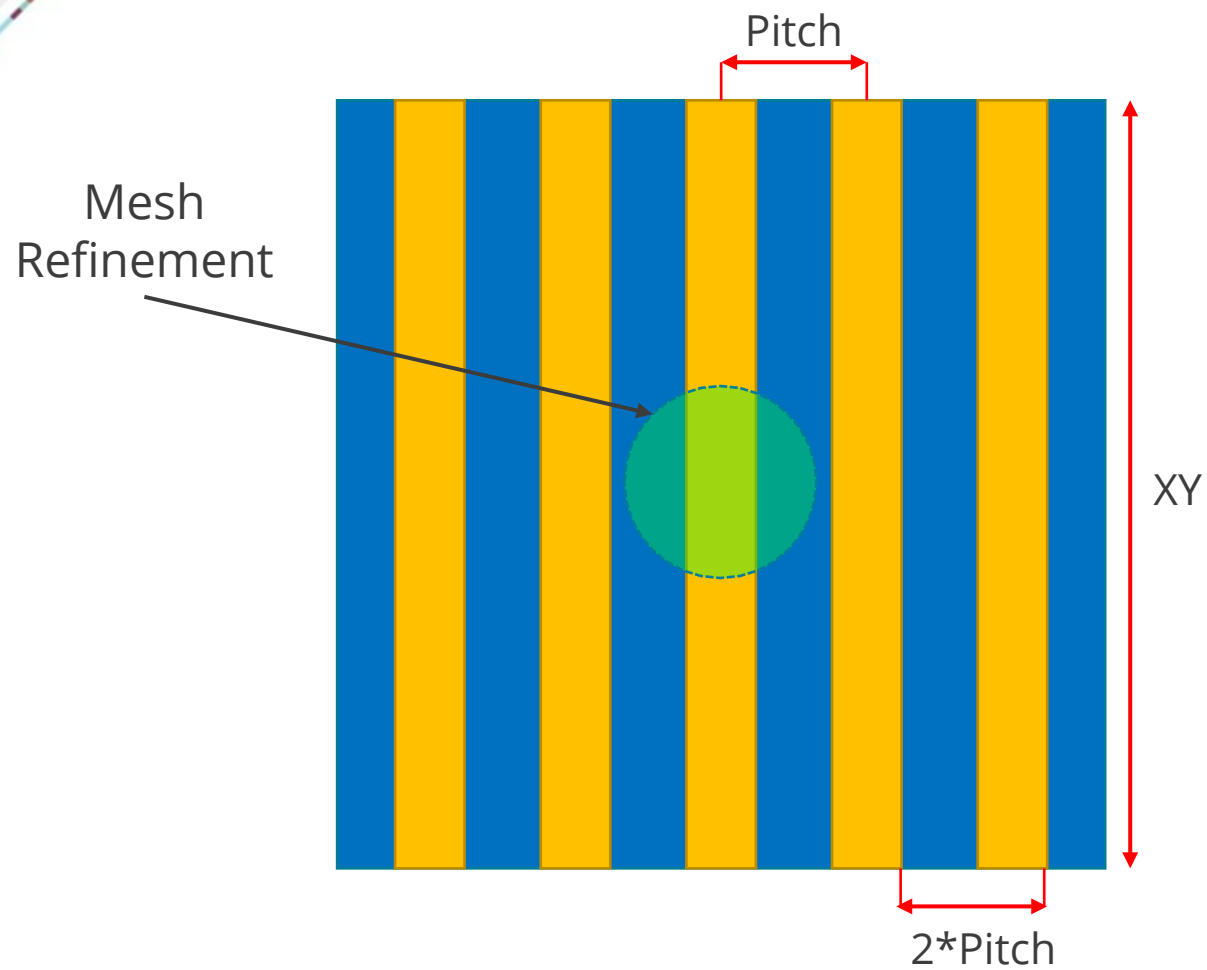


Match simulation with
experimental





Geometry - Wires

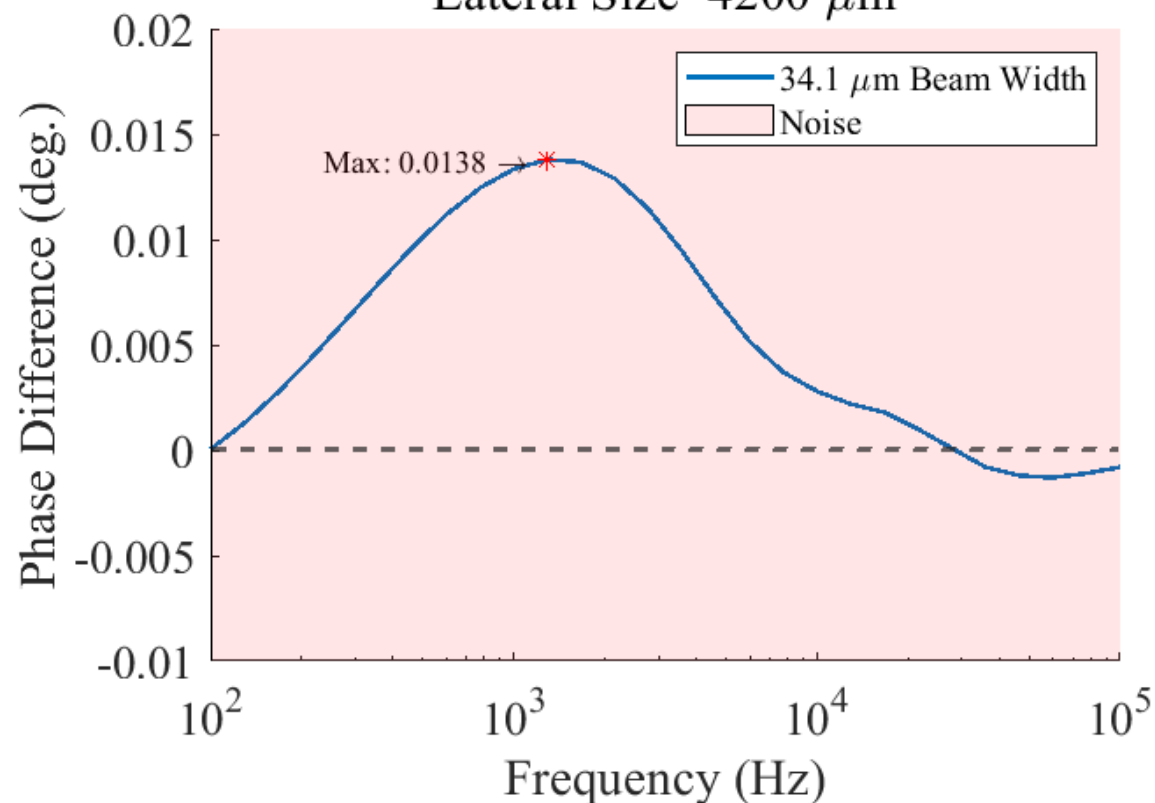




Simulation Results – 10 μm Pitch

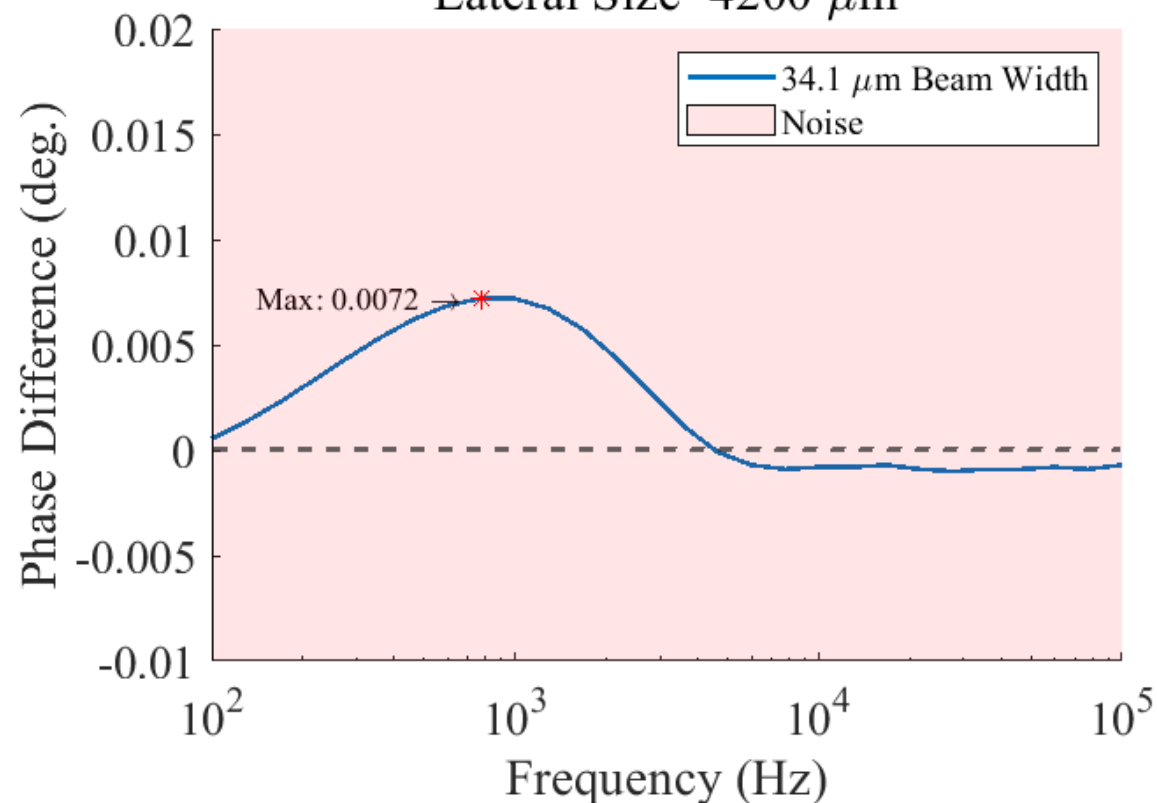
50 μm Si Chiplet with 10 μm Pitch

Lateral Size=4200 μm



100 μm Si Chiplet with 10 μm Pitch

Lateral Size=4200 μm

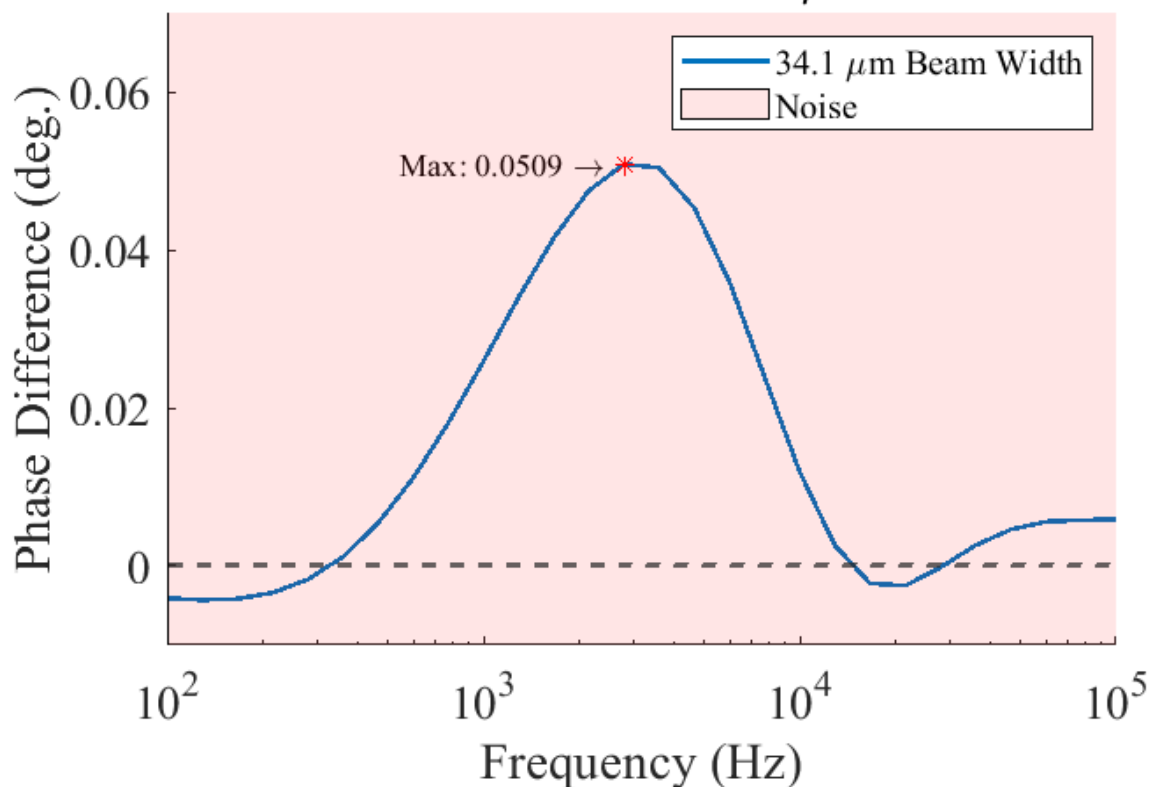




Simulation Results – 33 μm Pitch

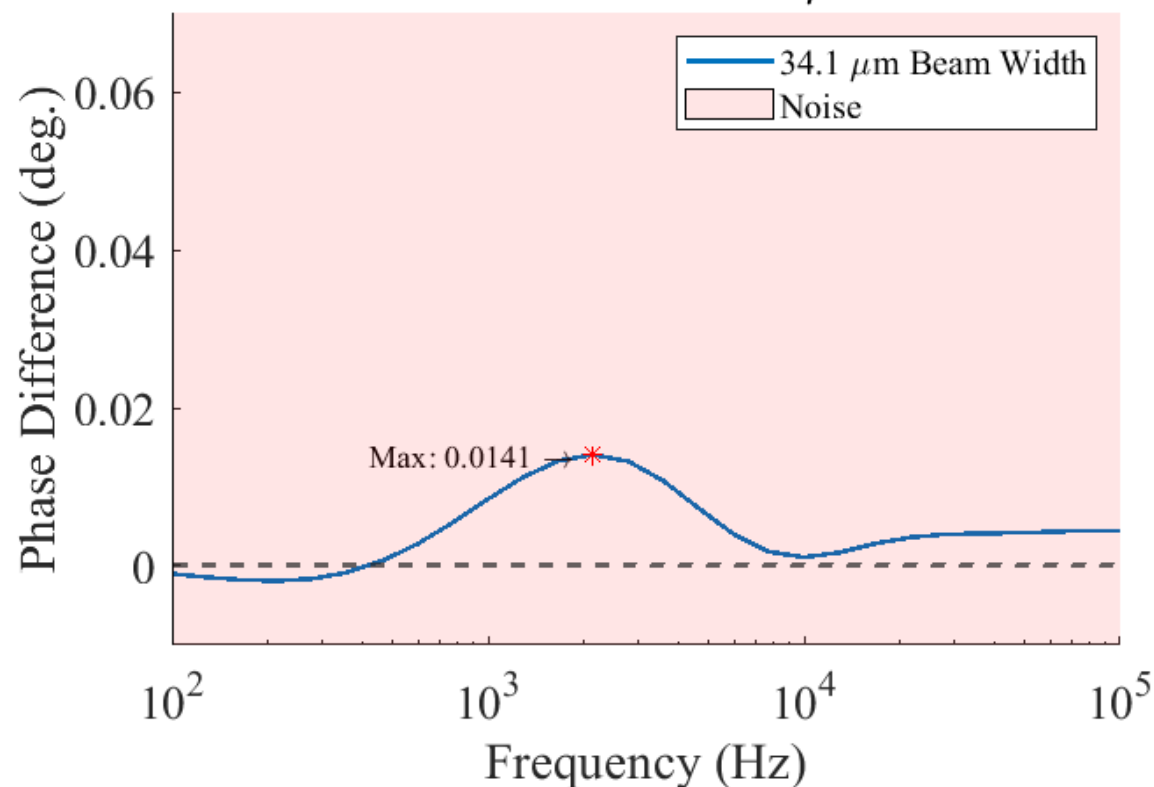
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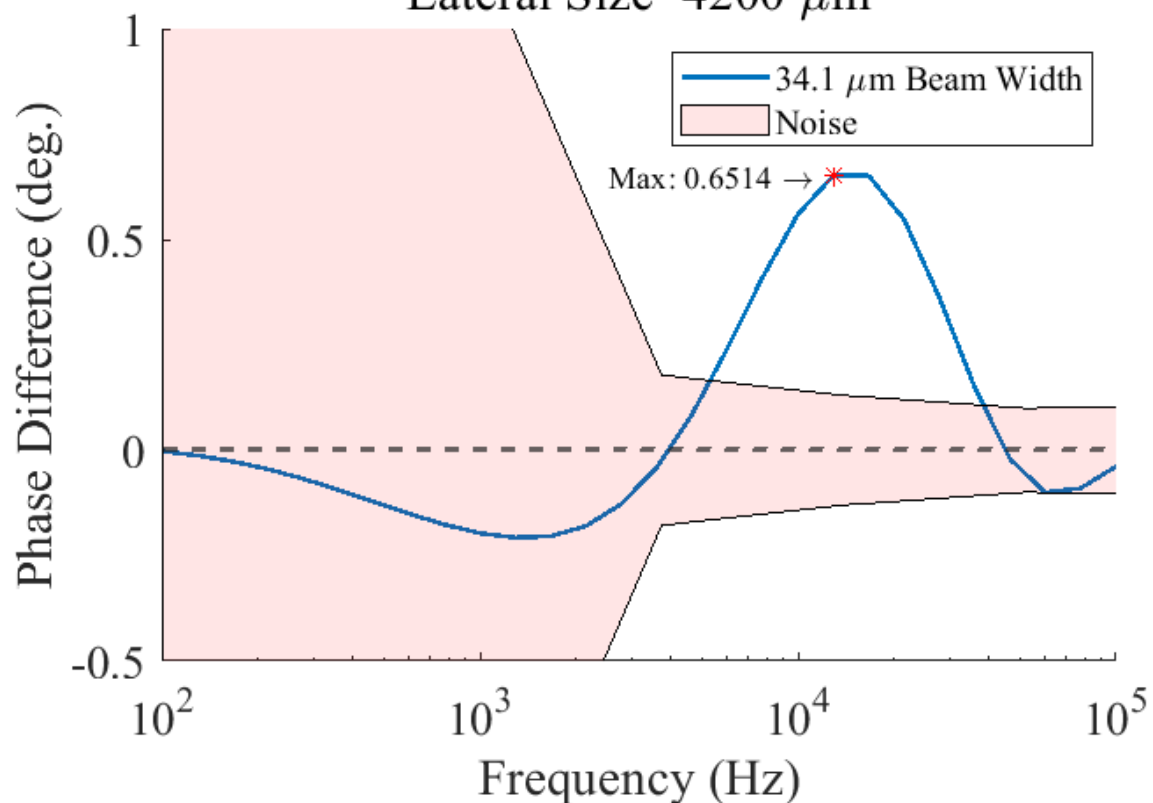




Simulation Results – 100 μm Pitch

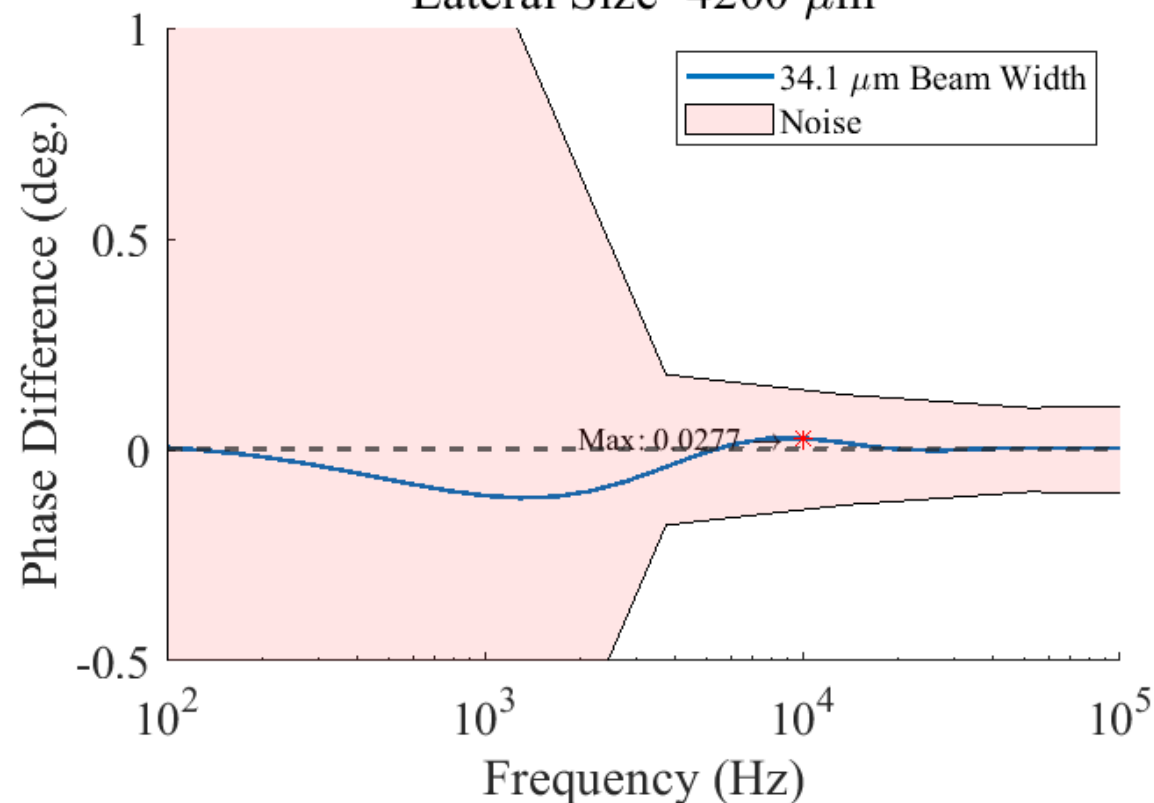
50 μm Si Chiplet with 100 μm Pitch

Lateral Size=4200 μm



50 μm Si Chiplet with 100 μm Pitch

Lateral Size=4200 μm





Conclusions and Team

- FDTR is on its way to non-destructive monitoring
- Discovered several errors in modelling that have been or are in the process of being resolved
- Noise floor comparison performed to show potential lateral resolution limits
- Ability to perform subsurface imaging on a micro-scale

FDTR/Optics

- Amun Jarzembski
- Anthony McDonald

Code development

- Ben Treweek
- Tim Walsh

Applications

- Greg Pickrell
- Matt Jordan
- Paul Clem
- Derek Wilke

Thermal modeling

- Wyatt Hodges
- Brenden Herkenhoff